

## FEATURES

High density cell design for low RDS(ON)

Voltage controlled small signal switch.

Rugged and reliable.

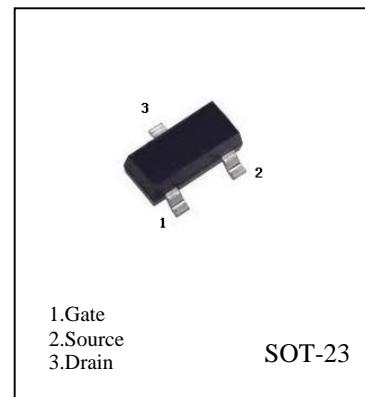
High saturation current capability.

## MAXIMUM RATINGS (TA=25°C unless otherwise noted)

Symbol	Parameter	Ratings	Unit
V <sub>DS</sub>	Drain-source voltage (V <sub>GS</sub> = 0)	60	V
V <sub>DGR</sub>	Drain-gate voltage (R <sub>GS</sub> = 20 kΩ)	60	V
V <sub>GS</sub>	Gate- source voltage	±15	V
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 25°C	0.35	A
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	800	mA
P <sub>TOT</sub>	Total dissipation at T <sub>C</sub> = 25°C	0.85	W
R <sub>thj- amb</sub>	Thermal resistance junction-ambient max	357.1 <sup>(2)</sup>	°C/W
T <sub>J</sub> , T <sub>stg</sub>	Operating junction temperature, Storage temperature	- 55 to 150 °C	

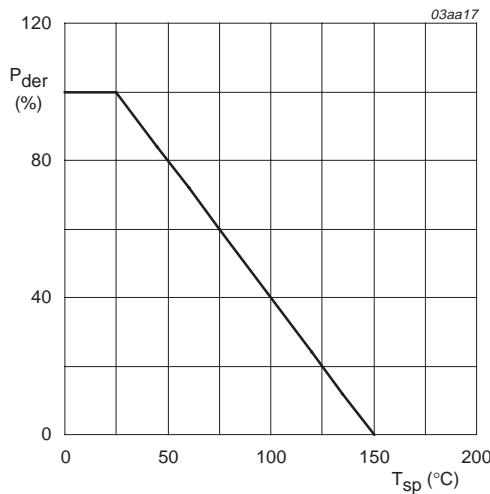
**2N7002K**

N-Channel MOSFET



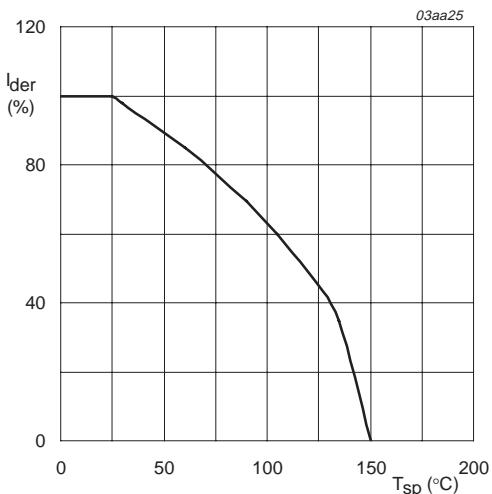
## ELECTRICAL CHARACTERISTICS (Tamb=25°C unless otherwise specified)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>Static characteristics</b>						
V <sub>(BR)DSS</sub>	drain-source breakdown voltage	I <sub>D</sub> = 10 μA; V <sub>GS</sub> = 0 V				
		T <sub>j</sub> = 25 °C	60	75	-	V
		T <sub>j</sub> = -55 °C	55	-	-	V
V <sub>(BR)GSS</sub>	drain-source breakdown voltage	I <sub>G</sub> = ±1 mA; V <sub>DS</sub> = 0 V	16	22	-	V
V <sub>GS(th)</sub>	gate-source threshold voltage	I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; Figure 9				V
		T <sub>j</sub> = 25 °C	1	2	-	V
		T <sub>j</sub> = 150 °C	0.6	-	-	V
		T <sub>j</sub> = -55 °C	-	-	3.5	V
I <sub>DSS</sub>	drain-source leakage current	V <sub>DS</sub> = 48 V; V <sub>GS</sub> = 0 V				
		T <sub>j</sub> = 25 °C	-	0.01	1	μA
		T <sub>j</sub> = 150 °C	-	-	10	μA
I <sub>GSS</sub>	gate-source leakage current	V <sub>GS</sub> = ±10 V; V <sub>DS</sub> = 0 V	-	50	500	nA
R <sub>DSON</sub>	drain-source on-state resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 500 mA; Figure 7 and 8				
		T <sub>j</sub> = 25 °C	-	2.8	3.9	Ω
		T <sub>j</sub> = 150 °C	-	5.2	7.2	Ω
		V <sub>GS</sub> = 4.5 V; I <sub>D</sub> = 200 mA; Figure 7 and 8	-	3.8	5.3	Ω
<b>Dynamic characteristics</b>						
C <sub>iss</sub>	input capacitance	V <sub>GS</sub> = 0 V; V <sub>DS</sub> = 10 V; f = 1 MHz; Figure 11	-	13	40	pF
C <sub>oss</sub>	output capacitance		-	8	30	pF
C <sub>rss</sub>	reverse transfer capacitance		-	4	10	pF
t <sub>on</sub>	turn-on time	V <sub>DD</sub> = 50 V; R <sub>L</sub> = 250 Ω;	-	3	10	ns
t <sub>off</sub>	turn-off time	V <sub>GS</sub> = 10 V; R <sub>G</sub> = 50 Ω; R <sub>GS</sub> = 50 Ω	-	9	15	ns
<b>Source-drain diode</b>						
V <sub>SD</sub>	source-drain (diode forward) voltage	I <sub>S</sub> = 300 mA; V <sub>GS</sub> = 0 V; Figure 12	-	0.93	1.5	V
t <sub>rr</sub>	reverse recovery time	I <sub>S</sub> = 300 mA; dI <sub>S</sub> /dt = -100 A/μs; V <sub>GS</sub> = 0 V; V <sub>R</sub> = 25 V	-	30	-	ns
Q <sub>r</sub>	recovered charge		-	30	-	nC

**2N7002K Typical Characteristics**


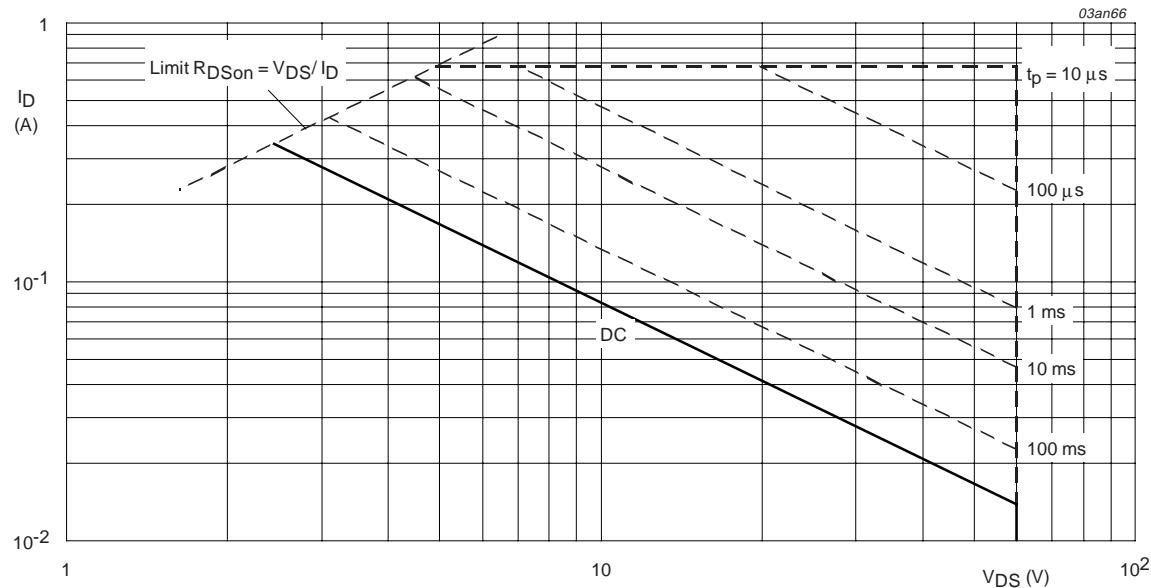
$$P_{der} = \frac{P_{tot}}{P_{tot}(25^\circ C)} \times 100\%$$

**Fig 1.** Normalized total power dissipation as a function of solder point temperature.



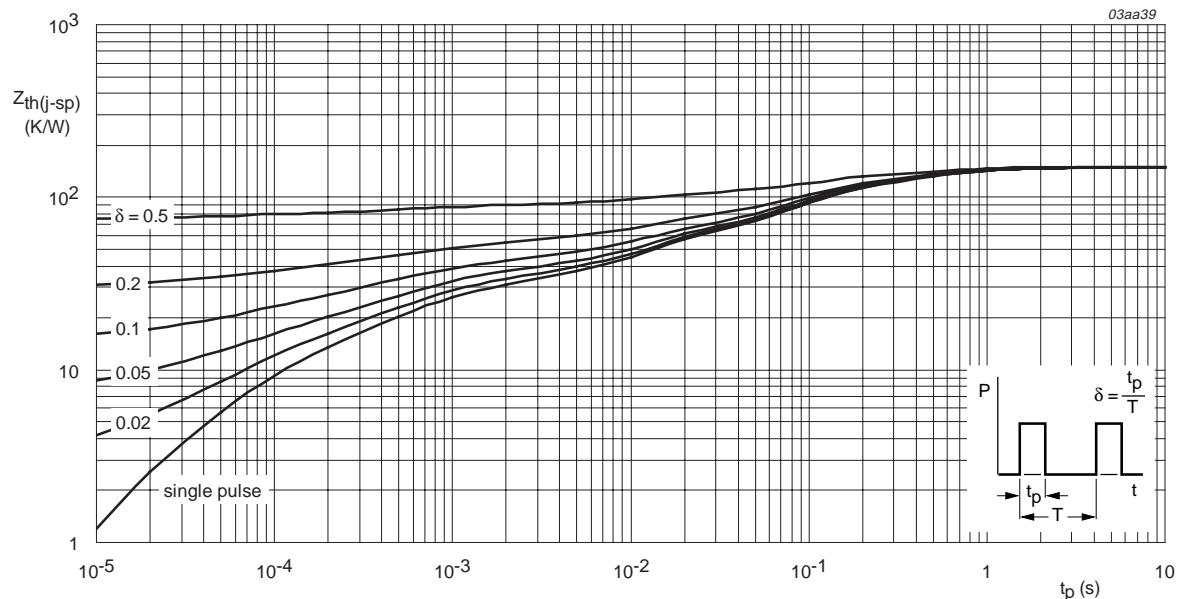
$$I_{der} = \frac{I_D}{I_{D(25^\circ C)}} \times 100\%$$

**Fig 2.** Normalized continuous drain current as a function of solder point temperature.

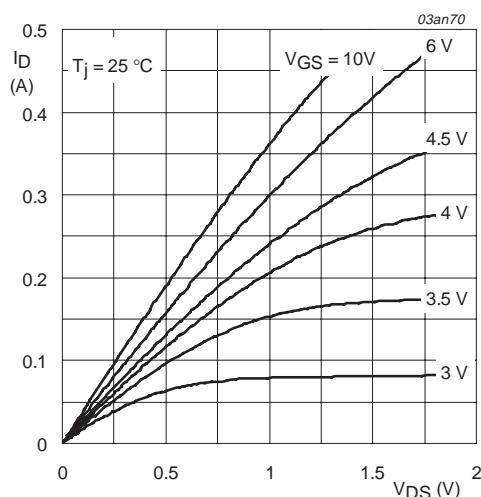


$T_{sp} = 25^\circ C$ ;  $I_{DM}$  is single pulse;  $V_{GS} = 10 V$

**Fig 3.** Safe operating area; continuous and peak drain currents as a function of drain-source voltage.

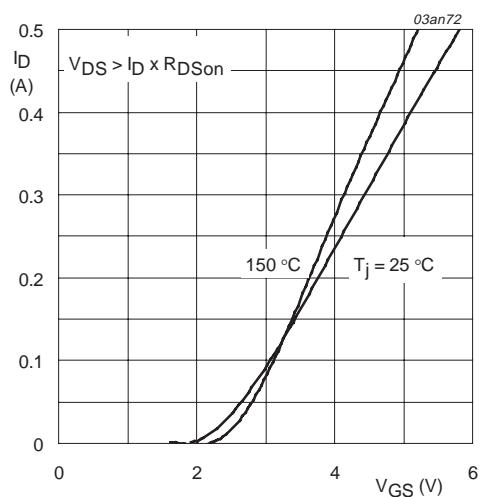
**2N7002K** Typical Characteristics


**Fig 4.** Transient thermal impedance from junction to solder point as a function of pulse duration.



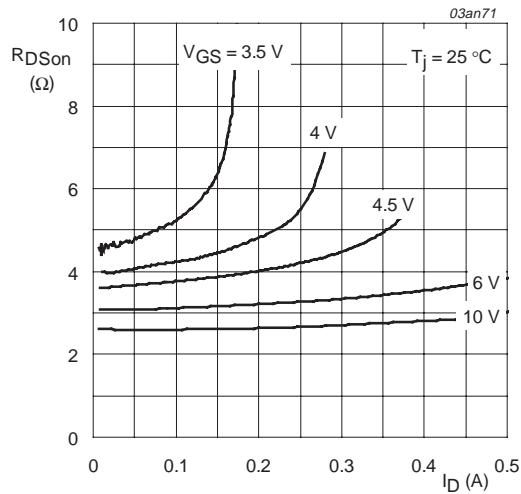
$T_j = 25^\circ C$

**Fig 5.** Output characteristics: drain current as a function of drain-source voltage; typical values.

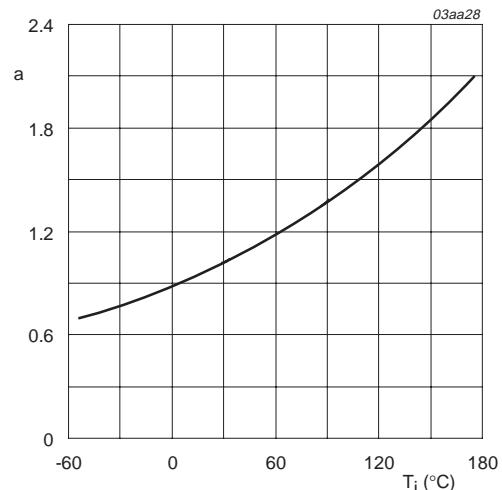


$T_j = 25^\circ C$  and  $150^\circ C$ ;  $V_{DS} > I_D \times R_{DSon}$

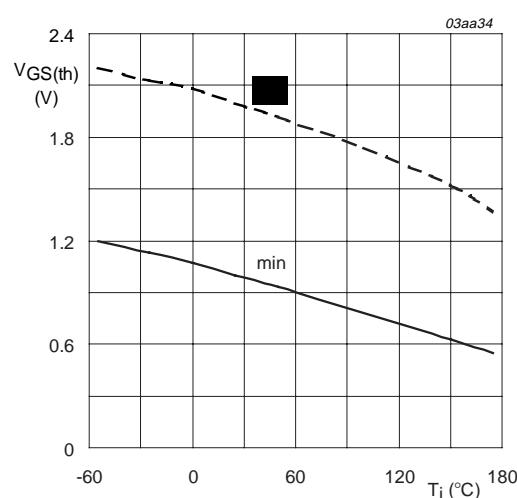
**Fig 6.** Transfer characteristics: drain current as a function of gate-source voltage; typical values.

**2N7002K Typical Characteristics**


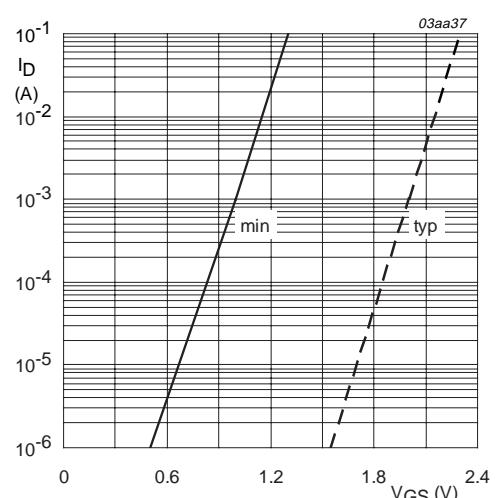
**Fig 7.** Drain-source on-state resistance as a function of drain current; typical values.



**Fig 8.** Normalized drain-source on-state resistance factor as a function of junction temperature.

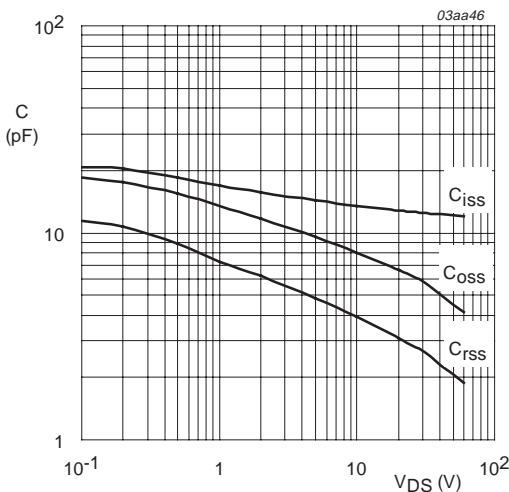


**Fig 9.** Gate-source threshold voltage as a function of junction temperature.



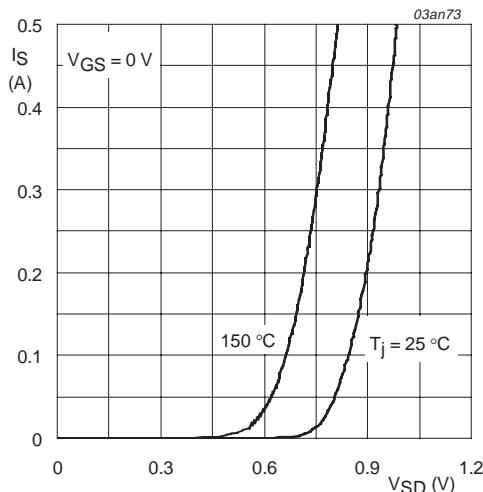
**Fig 10.** Sub-threshold drain current as a function of gate-source voltage.

## 2N7002K Typical Characteristics



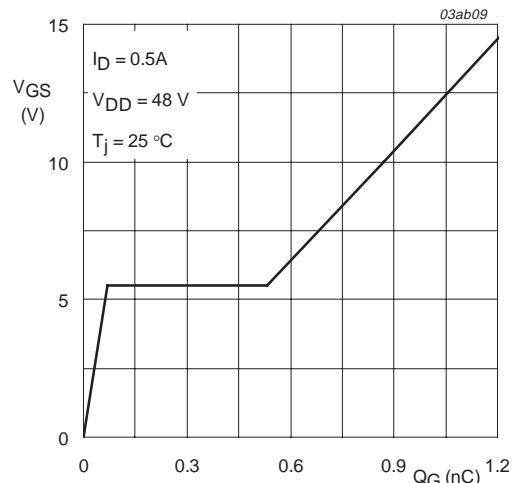
$V_{GS} = 0$  V;  $f = 1$  MHz

Fig 11. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values.



$T_j = 25^\circ\text{C}$  and  $150^\circ\text{C}$ ;  $V_{GS} = 0$  V

Fig 12. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values.



$I_D = 0.5$  A;  $V_{DD} = 48$  V

Fig 13. Gate-source voltage as a function of gate charge; typical values.